dvanced PECVD-LS Nitride2( n=1.93,-40MPa, 8.3nm/min)				Advanced PECVD Typical Film Properties
S Nitride 2 depostion~2400A, 300C				Calibrated every 2-4 weeks
ep1:	NITRIDE2 coat			Check for the latest update on UCSB Nanofab WIKI
	Name	Value	Changeable	
	LF on time(ms)	1000ms	Υ	
	LF setpoint	80W*	Υ	* Always 90W, but adjusted 10/17/17 to lower stress!
	Process pressure	800 mtorr	N	
	RF on time(ms)	6000ms	N	
	RF setpoint	30 W	N	
	stabilization time	15 seconds	N	
	step time(m)	10 min	Υ	
	step time(s)	0 sec	Υ	
	2%SiH4 %He	1040sccm	N	
	N2	980sccm	N	
	NH3	18sccm	N	
tep2:	NITRIDE2 depositi	on		LS Nitride2~2400A Typical Film Properties
	Name	Value	Changeable	Deposition rate~8 nm/min
	LF on time(ms)	1000ms	Y	Refractive index@632.8nm=1.959
	LF setpoint	80W*	Υ	Stress~7MPa
	Process pressure	800 mtorr	N	HF etch rate~36 nm/min
	RF on time(ms)	6000ms	N	Gain 4 0.16-1.6)um particles from film ONLY:~1500-2000
	RF setpoint	30 W	N	Gain2 (2.8-28)um paricles from film ONLY:~15-26
	stabilization time	15 seconds	N	Average uniformity (within the wafer) is ~ 99.4%
	step time(m)	30 min	Υ	
	step time(s)	0 sec	Υ	
	2%SiH4 %He	1040sccm	N	
	N2	980sccm	N	
	NH3	18sccm	N	
ten3:	STANDARD PLASM		,	
	1. pump down			
	Name	Value	Changeable	
	stabilization time	15 seconds	N	
	step time(m)	0	N	
	step time(s)	30	N	
	2. Pre-purge			
	Name	Value	Changeable	
	purge	1 (Yes/No)	N	
	stabilization time	15 seconds	N	
	step time(m)	1	N	
	step time(sec)	0	N	
	3.1 High Pressure			
	Name	Value	Changeable	
	Cload position	50%	N	
	Ctune position	50%	N	
	DriveMatch	1 (Yes/No)	N	
	Process pressure	600 mtorr	N	
	RF setpoint=300	300 W	N	
			N N	
	Stabilization time	35 seconds ENTER TIME	Y	For 7min/ costs denocition) was 1min Standard Plants Class
	step time(m) step time(s)	0	Y	For 7min( coat+deposition) run 1min Standard Plasma Clean  Run longer clean, (10-20%) more, only if chamber does not look cle

